



**Committee on Education (Standing Committee of the NPC)**

Chair: Bruce Harding, CEIR, Purdue University

Staff: Lisa Rajchel

**Voting Members: (36)**

Ms. Joyce Abrams, ASHRAE (2012)  
Mr. Thomas Applegate, ACTE (2012)  
Mr. Vince Baclawski, NEMA (2012)  
Ms. Monica Barone, Qualcomm (2012)  
Mr. Rich DePue, American Welding Society (2012)  
Mr. Donald Deutsch, Oracle (2012)  
Dr. Stephen J. Elliott, Purdue University (2012)  
Ms. Joy Fitzpatrick, The Boeing Company (2012)  
Mr. Richard Forselius, Standards Mgmt. Int'l. (2012)  
Dr. Arlen Gullickson, Western Michigan University (2012)  
Ms. Dorothy Harris, ICC (2012)  
Mr. Stan Hazan, NSF International (2010)  
Mr. Daryl Hunt, Eastman Kodak (2010)  
Mr. Robert D. Hunter, P.E., Robert Hunter Assoc. (2012)

Mr. Edward F. Mikowski, Jr., ECA (2012)  
Mr. Steve Mills, Hewlett-Packard (2012)  
Ms. Ashley Moore, U.S. Dept. of Homeland Security (2012)  
Mr. Steve Mutkoski, Microsoft (2012)  
Mr. Robert Noth (2012)  
Mr. Jim Olshefsky, ASTM International (2010)  
Ms. Deborah Prince, Underwriters Laboratories (2012)  
Dr. Katherine D. Seelman, Univ. of Pittsburgh (2012)  
Dr. Timonthy Smith, University of Minnesota (2012)  
Mr. Nancy Start, Clinical Device Group (2012)  
Ms. Susan Tatiner, IEEE (2012)  
Mr. Lee Webster, Society for HR Management (2012)  
Mr. Jefferson Welch, Carnegie Mellon University (2012)  
Mr. Philip Wennblom, Intel (2012)

Mr. Frankie S. Jones, AT&T Business Learning Services (2012)  
Mr. Stuart Karasik, Utilities Group (2012)  
Ms. Liz Kerrigan, Infectious Diseases, ATCC (2012)  
Mr. Stephen Kwan, San Jose State University (2010)

Ms. Trudie Williams, U.S. DoD (2012)  
Mr. George Willingmyre, GTW Associates (2012)  
Mr. John Toth, Intellectual Property Shield, Inc. (2010)  
Mr. Donald Yarbrough, Educational Evaluation (2012)

**Non-voting Members: (18)**

Mr. John Bagby, Penn State University  
Mr. Dan Bart, Valley View Corporation  
Mr. Brad Biddle, Intel  
Ms. Betsy Fanning, AIIM  
Ms. Susan Hoyler, Qualcomm  
Mr. Tim Koczanski, Department of Defense  
Mr. John Kulick, Siemens Corporate Research  
Mr. Dennis Marks, American Welding Society  
Ms. Jennifer McClain, IEEE

Mr. Eric Puskar, NIST  
Mr. Steve Mills, IEEE  
Mr. Donald Purcell, The Center for Global Standards Analysis  
Ms. Alison C. Ruger, IHS Global Inc.  
Dr. John R. Sanders, JRS Consulting  
Dr. Timothy Schoechle, ICSR, Univ. of Colorado  
Ms. Anne Sharkey, Standards Council of Canada  
Mr. Ron Silletti, IBM  
Mr. Glenn Tubrett, Canadian Standards Association